

Search Notes



Application/Control No.

10/608,771

Examiner

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Applicant(s)/Patent under Reexamination

EIDEN, NIKO

Art Unit

2685 2618

SEARCHED

Class	Subclass	Date	Examiner
455	567		
	414.1		
	414.2		
	415		
	401		
340	7.52		
	7.6	10/27/05	DN
Updated		4/11/06	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	10/22/2005	DN
EAST	10/27/2005	DN